HEF4013B

Dual D-type flip-flop Rev. 8 — 21 November 2011

Product data sheet

1. **General description**

The HEF4013B is a dual D-type flip-flop that features independent set-direct input (SD), clear-direct input (CD), clock input (CP) and outputs (Q, Q). Data is accepted when CP is LOW and is transferred to the output on the positive-going edge of the clock. The active HIGH asynchronous CD and SD inputs are independent and override the D or CP inputs. The outputs are buffered for best system performance. The clock input's Schmitt-trigger action makes the circuit highly tolerant of slower clock rise and fall times.

It operates over a recommended V_{DD} power supply range of 3 V to 15 V referenced to V_{SS} (usually ground). Unused inputs must be connected to V_{DD}, V_{SS}, or another input.

Features and benefits 2.

- Tolerant of slow clock rise and fall times
- Fully static operation
- 5 V, 10 V, and 15 V parametric ratings
- Standardized symmetrical output characteristics
- Specified from –40 °C to +125 °C
- Complies with JEDEC standard JESD 13-B

3. Applications

- Counters and dividers
- Registers
- Toggle flip-flops

Ordering information

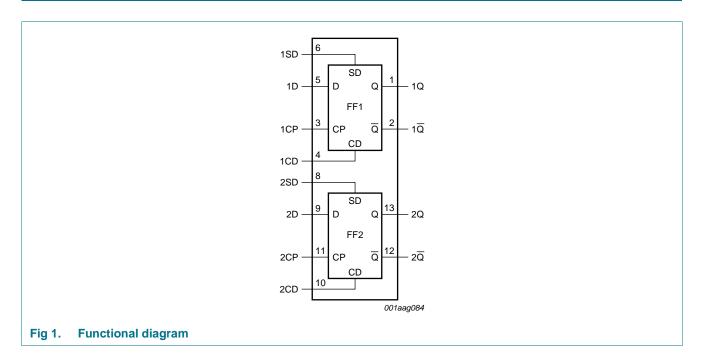
Table 1. **Ordering information**

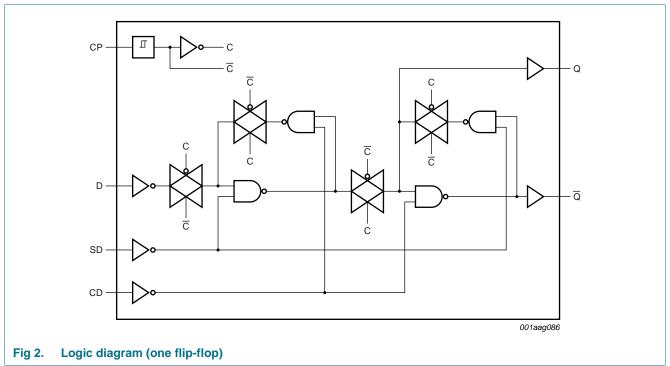
All types operate from -40 °C to +125 °C

Type number	Package	Package									
	Name	Description	Version								
HEF4013BP	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1								
HEF4013BT	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1								
HEF4013BTT	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1								



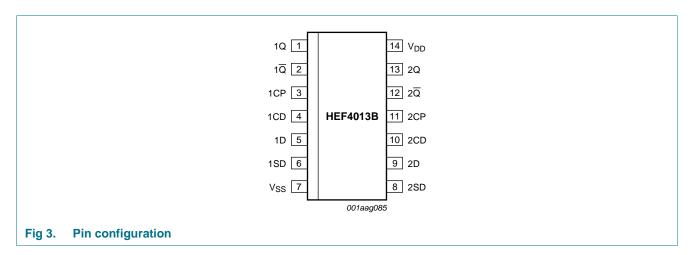
5. Functional diagram





6. Pinning information

6.1 Pinning



6.2 Pin description

Table 2. Pin description

	-	
Symbol	Pin	Description
1Q, 2Q	1, 13	true output
1Q, 2Q	2, 12	complement output
1CP, 2CP	3, 11	clock input (LOW to HIGH edge-triggered)
1CD, 2CD	4, 10	asynchronous clear-direct input (active HIGH)
1D, 2D	5, 9	data input
1SD, 2SD	6, 8	asynchronous set-direct input (active HIGH)
V_{SS}	7	ground (0 V)
V_{DD}	14	supply voltage

7. Functional description

Table 3. Function table[1]

Control			Input	Output	Output		
nSD	nCD	nCP	nD	nQ	nQ		
Н	L	X	X	Н	L		
L	Н	X	Χ	L	Н		
Н	Н	X	Χ	Н	Н		
L	L	↑	L	L	Н		
L	L	\uparrow	Н	Н	L		

^[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; $\uparrow = LOW \text{-to-HIGH clock transition}$.

8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to V_{SS} = 0 V (ground).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DD}	supply voltage		-0.5	+18	V
I _{IK}	input clamping current	$V_I < -0.5 \text{ V or } V_I > V_{DD} + 0.5 \text{ V}$	-	±10	mA
VI	input voltage		-0.5	$V_{DD} + 0.5$	V
I _{OK}	output clamping current	V_{O} < -0.5 V or V_{O} > V_{DD} + 0.5 V	-	±10	mA
I _{I/O}	input/output current		-	±10	mA
I _{DD}	supply current		-	50	mA
T _{stg}	storage temperature		-65	+150	°C
T _{amb}	ambient temperature		-40	+125	°C
P _{tot}	total power dissipation	$T_{amb} = -40 ^{\circ}\text{C} \text{ to } +125 ^{\circ}\text{C}$			
		DIP14	<u>[1]</u> _	750	mW
		SO14	[2] _	500	mW
		TSSOP14	[3] _	500	mW
Р	power dissipation	per output	-	100	mW

^[1] For DIP14 packages: above T_{amb} = 70 °C, P_{tot} derates linearly with 12 mW/K.

9. Recommended operating conditions

Table 5. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DD}	supply voltage		3	15	V
VI	input voltage		0	V_{DD}	V
T _{amb}	ambient temperature		-40	+125	°C
Δt/ΔV	input transition rise and fall rate	$V_{DD} = 5 V$	-	3.75	μs/V
		V _{DD} = 10 V	-	0.5	μs/V
		V _{DD} = 15 V	-	0.08	μs/V

^[2] For SO14 packages: above T_{amb} = 70 °C, P_{tot} derates linearly with 8 mW/K.

^[3] For TSSOP14 packages: above T_{amb} = 60 °C, P_{tot} derates linearly with 5.5 mW/K.

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10. Static characteristics

Table 6. Static characteristics

 $V_{SS} = 0$ V; $V_I = V_{SS}$ or V_{DD} ; unless otherwise specified.

Symbol	Parameter	Conditions	V_{DD}	T _{amb} =	–40 °C	T _{amb} =	+25 °C	T _{amb} =	+85 °C	T _{amb} = +125 °C		Unit
				Min	Max	Min	Max	Min	Max	Min	Max	
V_{IH}	HIGH-level	$ I_{O} < 1 \mu A$	5 V	3.5	-	3.5	-	3.5	-	3.5	-	V
	input voltage		10 V	7.0	-	7.0	-	7.0	-	7.0	-	V
			15 V	11.0	-	11.0	-	11.0	-	11.0	-	V
V_{IL}	LOW-level	$ I_0 < 1 \mu A$	5 V	-	1.5	-	1.5	-	1.5	-	1.5	V
	input voltage		10 V	-	3.0	-	3.0	-	3.0	-	3.0	V
			15 V	-	4.0	-	4.0	-	4.0	-	4.0	V
V_{OH}	HIGH-level	$ I_{O} < 1 \mu A$	5 V	4.95	-	4.95	-	4.95	-	4.95	-	V
	output voltage		10 V	9.95	-	9.95	-	9.95	-	9.95	-	V
			15 V	14.95	-	14.95	-	14.95	-	14.95	-	V
-	LOW-level	$ I_O < 1 \mu A$	5 V	-	0.05	-	0.05	-	0.05	-	0.05	V
	output voltage		10 V	-	0.05	-	0.05	-	0.05	-	0.05	V
			15 V	-	0.05	-	0.05	-	0.05	-	0.05	V
I _{OH}	HIGH-level output current	$V_0 = 2.5 \text{ V}$	5 V	-	-1.7	-	-1.4	-	-1.1	-	-1.1	mΑ
		$V_0 = 4.6 \text{ V}$	5 V	-	-0.64	-	-0.5	-	-0.36	-	-0.36	mΑ
		$V_0 = 9.5 \text{ V}$	10 V	-	-1.6	-	-1.3	-	-0.9	-	-0.9	mΑ
		$V_0 = 13.5 \text{ V}$	15 V	-	-4.2	-	-3.4	-	-2.4	-	-2.4	mΑ
I_{OL}	LOW-level	$V_O = 0.4 V$	5 V	0.64	-	0.5	-	0.36	-	0.36	-	mΑ
	output current	$V_0 = 0.5 \ V$	10 V	1.6	-	1.3	-	0.9	-	0.9	-	mΑ
		$V_0 = 1.5 \text{ V}$	15 V	4.2	-	3.4	-	2.4	-	2.4	-	mΑ
l _l	input leakage current		15 V	-	±0.1	-	±0.1	-	±1.0	-	±1.0	μΑ
I _{DD}	supply current	all valid input	5 V	-	1.0	-	1.0	-	30	-	30	μΑ
		combinations; $ I_O = 0 \text{ A}$	10 V	-	2.0	-	2.0	-	60	-	60	μΑ
		10 = 0 A	15 V	-	4.0	-	4.0	-	120	-	120	μΑ
C _I	input capacitance		-	-	-	-	7.5	-	-	-	-	pF

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11. Dynamic characteristics

Table 7. Dynamic characteristics

 $T_{amb} = 25$ °C; unless otherwise specified. For test circuit see <u>Figure 6</u>.

Symbol	Parameter	Conditions	V_{DD}	Extrapolation formula	Min	Тур	Max	Unit
t _{PHL}	HIGH to LOW	nCP to nQ, $n\overline{Q}$;	5 V	[1] $83 + 0.55 \times C_L$	-	110	220	ns
	propagation delay	see Figure 4	10 V	$34 + 0.23 \times C_L$	-	45	90	ns
			15 V	$22 + 0.16 \times C_{L}$	-	30	60	ns
		nSD to nQ	5 V	11 73 + $0.55 \times C_L$	-	100	200	ns
			10 V	$29 + 0.23 \times C_L$	-	40	80	ns
			15 V	$22 + 0.16 \times C_{L}$	-	30	60	ns
		nCD to nQ	5 V	11 73 + 0.55 × C _L	-	100	200	ns
			10 V	$29 + 0.23 \times C_L$	-	40	80	ns
			15 V	$22 + 0.16 \times C_L$	-	30	60	ns
t _{PLH}	LOW to HIGH	nCP to nQ, $n\overline{Q}$;	5 V	11 68 + 0.55 × C _L	-	95	190	ns
	propagation delay	see Figure 4	10 V	$29 + 0.23 \times C_L$	-	40	80	ns
			15 V	$22 + 0.16 \times C_L$	-	30	60	ns
		nSD to nQ	5 V	[1] 48 + 0.55 × C _L	-	75	150	ns
			10 V	$24 + 0.23 \times C_L$	-	35	70	ns
			15 V	17 + 0.16 × C _L	-	25	50	ns
		nCD to nQ	5 V	[1] 33 + 0.55 × C _L	-	60	120	ns
			10 V	19 + 0.23 × C _L	-	30	60	ns
			15 V	12 + 0.16 × C _L	-	20	40	ns
t _t	transition time	see Figure 4	5 V	[1] 10 + 1.00 × C _L	-	60	120	ns
			10 V	9 + 0.42 × C _L	-	30	60	ns
			15 V	$6 + 0.28 \times C_L$	-	20	40	ns
t _{su}	set-up time	nD to nCP;	5 V		40	20	-	ns
		see Figure 4	10 V		25	10	-	ns
			15 V		15	5	-	ns
t _h	hold time	nD to nCP;	5 V		20	0	-	ns
		see Figure 4	10 V		20	0	-	ns
			15 V		15	0	-	ns
t _W	pulse width	nCP input LOW;	5 V		60	30	-	ns
		see Figure 4	10 V		30	15	-	ns
			15 V		20	10	-	ns
		nSD input HIGH;	5 V		50	25	-	ns
		see Figure 5	10 V		24	12	-	ns
			15 V		20	10	-	ns
		nCD input HIGH;	5 V		50	25	-	ns
		see Figure 5	10 V		24	12	-	ns
			15 V		20	10	-	ns

Table 7. Dynamic characteristics ... continued

 $T_{amb} = 25$ °C; unless otherwise specified. For test circuit see <u>Figure 6</u>.

Symbol	Parameter	Conditions	V_{DD}	Extrapolation formula	Min	Тур	Max	Unit
t_{rec}	recovery time	nSD input;	5 V		+15	-5	-	ns
		see <u>Figure 5</u>	10 V		15	0	-	ns
			15 V		15	0	-	ns
		nCD input; see <u>Figure 5</u>	5 V		40	25	-	ns
			10 V		25	10	-	ns
			15 V		25	10	-	ns
f _{clk(max)}	maximum clock	see Figure 4	5 V		7	14	-	MHz
	frequency		10 V		14	28	-	MHz
			15 V		20	40	-	MHz

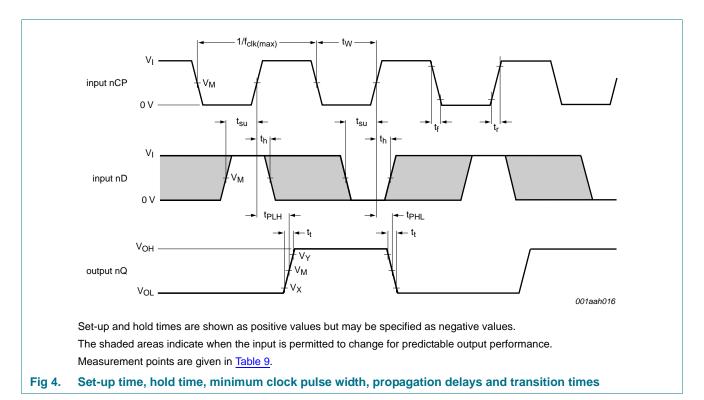
^[1] Typical values of the propagation delays and output transition times can be calculated with the extrapolation formulas. C_L is given in pF.

Table 8. Dynamic power dissipation

 $V_{SS} = 0 \ V; \ t_r = t_f \le 20 \ ns; \ T_{amb} = 25 \ ^{\circ}C.$

-	· · · · · · · · · · · · · · · · · · · ·			
Symbol	Parameter	V_{DD}	Typical formula	Where
P_D	dynamic power dissipation	5 V	$P_D = 850 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2 \ \mu W$	f_i = input frequency in MHz;
		10 V	$P_D = 3600 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2 \mu W$	fo = output frequency in MHz;
		15 V	$P_D = 9000 \times f_i + \Sigma (f_o \times C_L) \times V_{DD}^2 \mu W$	C_L = output load capacitance in pF;
				$\Sigma(f_0 \times C_L)$ = sum of the outputs;
				V _{DD} = supply voltage in V.

12. Waveforms



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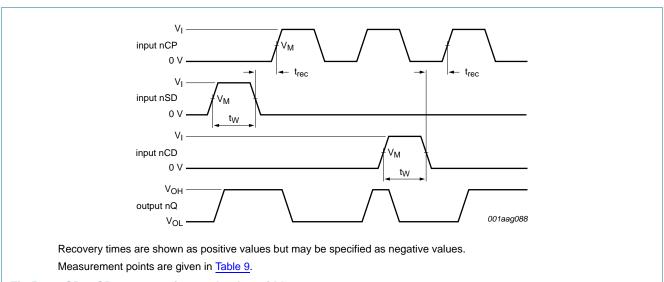
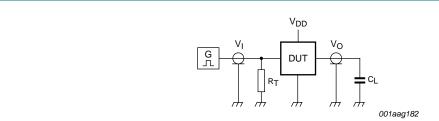


Fig 5. nSD, nCD recovery time and pulse width

Table 9. Measurement points

Supply voltage	Input	Output						
V_{DD}	V _M	V _M	V _X	V _Y				
5 V to 15 V	0.5V _{DD}	0.5V _{DD}	0.1V _{DD}	0.9V _{DD}				



Test and measurement data is given in Table 10;

Definitions test circuit:

DUT = Device Under Test.

 R_T = Termination resistance should be equal to output impedance Z_o of the pulse generator.

 C_L = Load capacitance including jig and probe capacitance.

Fig 6. Test circuit for measuring switching times

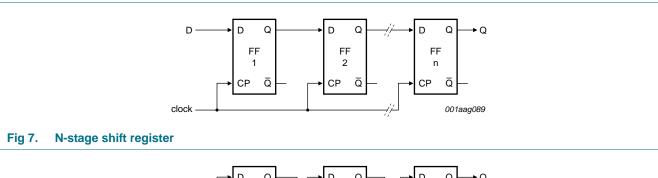
Table 10. Test data

Supply voltage	Input	Load	
V_{DD}	VI	t _r , t _f	CL
5 V to 15 V	V _{SS} or V _{DD}	≤ 20 ns	50 pF

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13. Application information



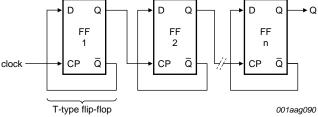


Fig 8. Binary ripple up-counter; divide-by-2ⁿ

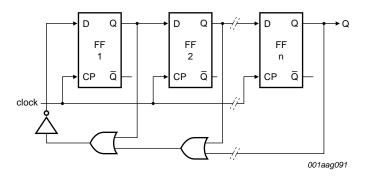
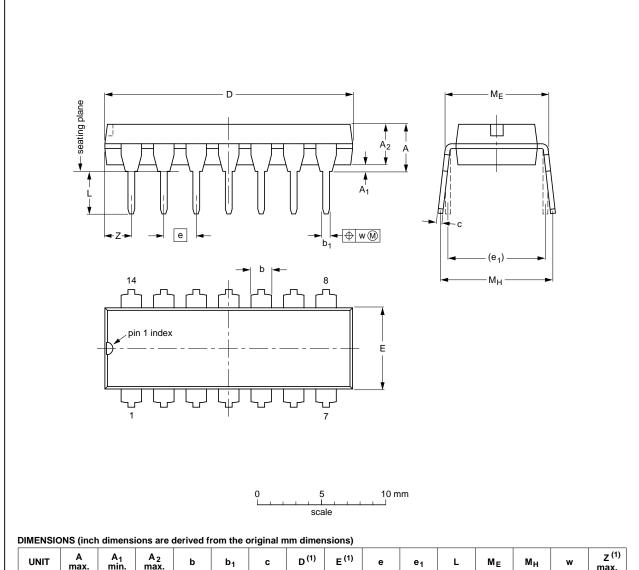


Fig 9. Modified ring counter; divide-by-(n + 1)

14. Package outline

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	С	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	ME	Мн	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.02	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.1	0.3	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

Note

1. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

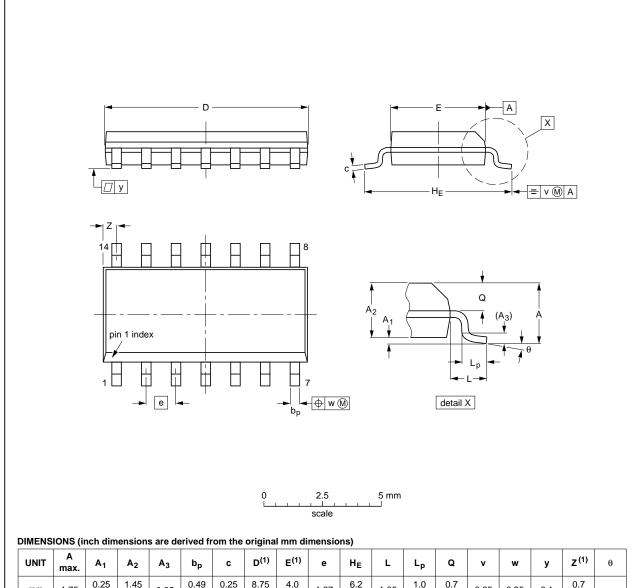
VERSION IEC JEDEC JEITA PROJECTION SOT27-1 050G04 MO-001 SC-501-14 \$\frac{99-12}{2}\$	OUTLINE		REFER	EUROPEAN	ISSUE DATE			
SO(27-1) = 0.50G04 = 0.001 = SC-501-14 = 0.001 = 0.0	VERSION	N IEC JEDEC		JEITA		PROJECTION	1330E DATE	
03-02	SOT27-1	050G04	MO-001	SC-501-14			99-12-27 03-02-13	

Fig 10. Package outline SOT27-1 (DIP14)

HEF4013

SO14: plastic small outline package; 14 leads; body width 3.9 mm

SOT108-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	HE	L	Lp	Q	v	w	у	z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.35 0.34	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	0°

Note

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT108-1	076E06	MS-012				99-12-27 03-02-19

Fig 11. Package outline SOT108-1 (SO14)

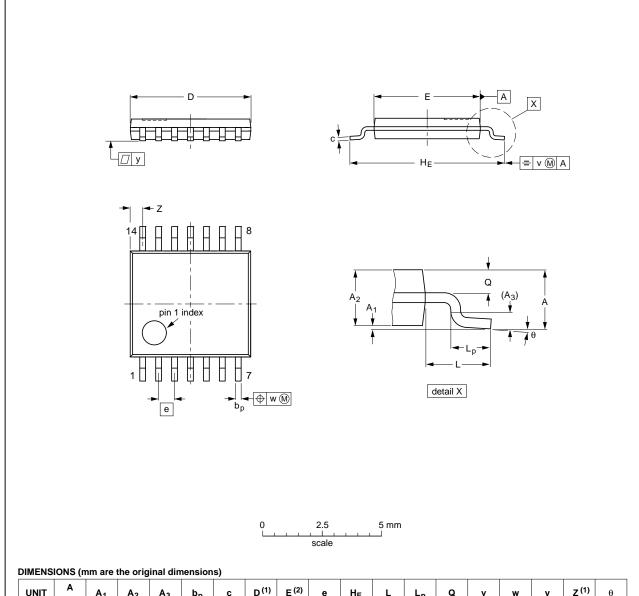
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TSSOP14: plastic thin shrink small outline package; 14 leads; body width 4.4 mm

SOT402-1



						-,												
UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	Q	v	w	у	Z ⁽¹⁾	θ
mm	1.1	0.15 0.05	0.95 0.80	0.25	0.30 0.19	0.2 0.1	5.1 4.9	4.5 4.3	0.65	6.6 6.2	1	0.75 0.50	0.4 0.3	0.2	0.13	0.1	0.72 0.38	8° 0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.
- 2. Plastic interlead protrusions of 0.25 mm maximum per side are not included.

PROJECTION	ISSUE DATE
PROJECTION	10002 5/112
	99-12-27 03-02-18

Fig 12. Package outline SOT402-1 (TSSOP14)

HEF4013B

15. Revision history

Table 11. Revision history

	-			
Document ID	Release date	Data sheet status	Change notice	Supersedes
HEF4013B v.8	20111121	Product data sheet	-	HEF4013B v.7
Modifications:	 Legal page: 	s updated.		
	 Changes in 	"General description", "Fea	tures and benefits" and	"Applications".
HEF4013B v.7	20110913	Product data sheet	-	HEF4013B v.6
HEF4013B v.6	20091027	Product data sheet	-	HEF4013B v.5
HEF4013B v.5	20090619	Product data sheet	-	HEF4013B v.4
HEF4013B v.4	20080515	Product data sheet	-	HEF4013B_CNV v.3
HEF4013B_CNV v.3	19950101	Product specification	-	HEF4013B_CNV v.2
HEF4013B_CNV v.2	19950101	Product specification	-	-

16. Legal information

16.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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Dual D-type flip-flop

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